## Notice of References Cited

Application/Control No. 10/517,623	Applicant(s)/Patent Under Reexamination YABE ET AL.		
Examiner	Art Unit		
Hee Soo Kim	2109	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,275,850 B1	08-2001	Beyda et al.	709/206
*	В	US-2002/0016818 A1	02-2002	Kirani et al.	709/203
*	С	US-2002/0138586 A1	09-2002	Paleiov et al.	709/207
*	D	US-2004/0049696 A1	03-2004	Baker et al.	713/201
*	Е	US-2005/0124337 A9	06-2005	Gresham et al.	455/431
*	F	US-7,117,246 B2	10-2006	Christenson et al.	709/206
	G	US-		·	
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
*	Z	JP 11272582 A	10-1999	Japan -	KAWAMURA, TAKUSHI	G06F 13/00	
	0						
	Р						
	Q	•					
	R						
	S						
	Т			29			

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ					
	v					
	w					
	x					

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.